

Dual P-Channel 30-V (D-S) MOSFET

G1 0

PRODUCT SUMMARY						
V _{DS} (V)	R _{DS(on)} (Ω)	I _D (A) ^{d, e}	Q _g (Typ.)			
- 30	0.029 at V _{GS} = - 10 V	- 7.3	17 nC			
	0.039 at V _{GS} = - 4.5 V	- 6.3	17110			

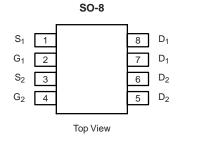
FEATURES

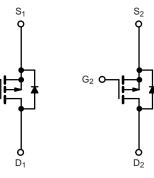
- Halogen-free
- TrenchFET[®] Power MOSFET
- 100 % UIS Tested

APPLICATIONS

Load Switches







P-Channel MOSFET

P-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS	_A = 25 °C, unless othe	erwise noted		
Parameter	Symbol	Limit	Unit	
Drain-Source Voltage	V _{DS}	- 30	V	
Gate-Source Voltage	V _{GS}	± 20	v	
	T _C = 25 °C		- 7.3 ^e	
Continuous Drain Current ($T_1 = 150 \ ^{\circ}C$)	T _C = 70 °C		- 7.0 ^e	
Continuous Drain Current (1j = 130 C)	T _A = 25 °C	I _D	- 7.3 ^{a, b}	
	T _A = 70 °C		- 5.9 ^{a, b}	Α
Pulsed Drain Current	I _{DM}	- 32 ^e	A	
Outline Output Date Diale Output	T _C = 25 °C	1.	- 4.1	
Continuous Source-Drain Diode Current	T _A = 25 °C	Is Is	- 2.0 ^{a, b}	
Avalanche Current	L = 0.1 mH	I _{AS}	- 20	
Single-Pulse Avalanche Energy	L = 0.1 IIIH	E _{AS}	20	mJ
	T _C = 25 °C		5.0	
Maximum Dawar Dissinction	T _C = 70 °C	D_	3.2	W
Maximum Power Dissipation	T _A = 25 °C	P _D	2.5 ^{a, b}	vv
	T _A = 70 °C	1	1.6 ^{a, b}	
Operating Junction and Storage Temperature Range	T _J , T _{stg}	- 55 to 150	°C	

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient ^{a, c}	t ≤ 10 s	R _{thJA}	38	50	°C/W	
Maximum Junction-to-Foot	Steady State	R _{thJF}	20	25	C/W	

Notes:

a. Surface mounted on 1" x 1" FR4 board.

b. t = 10 s.

c. Maximum under Steady State conditions is 85 °C/W.

d. Based on T_C = 25 °C.

e. Limited by package.

SPECIFICATIONS $T_J = 25 \degree C$ Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static				.,6.		•	
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} = 0 V, I _D = - 250 μA	- 30	1		V	
V _{DS} Temperature Coefficient	ΔV _{DS} /T _J			- 31		- mV/°C	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I _D = - 250 μA		4.5			
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} = V _{GS} , I _D = - 250 μA	- 1.0		- 3.0	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 V, V_{GS} = \pm 20 V$			± 100	nA	
_		$V_{DS} = -30 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$			- 1	μA	
Zero Gate Voltage Drain Current	IDSS	V _{DS} = - 30 V, V _{GS} = 0 V, T _J = 55 °C			- 5		
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge -10 \text{ V}, \text{ V}_{GS} = -10 \text{ V}$	- 30			Α	
	_ ` `	V _{GS} = - 10 V, I _D = - 6.3 A	0.035				
Drain-Source On-State Resistance ^a	R _{DS(on)}	V _{GS} = - 4.5 V, I _D = - 6.2 A		0.040		Ω	
Forward Transconductance ^a	9 _{fs}	V _{DS} = - 10 V, I _D = - 6.1 A		23		S	
Dynamic ^b				1	1	•	
Input Capacitance	C _{iss}			1350		pF	
Output Capacitance	C _{oss}	V _{DS} = - 15 V, V _{GS} = 0 V, f = 1 MHz		215			
Reverse Transfer Capacitance	C _{rss}			185			
Total Gate Charge		$V_{DS} = -15 \text{ V}, \text{ V}_{GS} = -10 \text{ V}, \text{ I}_{D} = -6.1 \text{ A}$		32	32 50		
	Qg			15	25	nC	
Gate-Source Charge	Q _{gs}	$V_{DS} = -15 \text{ V}, V_{GS} = -4.5 \text{ V}, I_{D} = -6.1 \text{ A}$		4			
Gate-Drain Charge	Q _{gd}			7.5			
Gate Resistance	R _g	f = 1 MHz		5.8		Ω	
Turn-On Delay Time	t _{d(on)}			10	15		
Rise Time	t _r	V_{DD} = - 15 V, R_L = 15 Ω		8	15	-	
Turn-Off DelayTime	t _{d(off)}	$I_D \cong$ - 1 A, V_{GEN} = - 10 V, R_g = 1 Ω		45	70		
Fall Time	t _f			12	25		
Turn-On Delay Time	t _{d(on)}			42	70	ns	
Rise Time	t _r	V_{DD} = - 15 V, R _L = 15 Ω		35	60		
Turn-Off DelayTime	t _{d(off)}	$I_D \cong$ - 1 A, V_{GEN} = - 4.5 V, R_g = 1 Ω		40	70		
Fall Time	t _f			16	30		
Drain-Source Body Diode Characterist	tics						
Continous Source-Drain Diode Current	۱ _S	T _C = 25 °C			- 4.1	A	
Pulse Diode Forward Current	I _{SM}				- 32	A	
Body Diode Voltage	V _{SD}	I _S = - 2 A, V _{GS} = 0 V		- 0.75	- 1.2	V	
Body Diode Reverse Recovery Time	t _{rr}			34	60	ns	
Body Diode Reverse Recovery Charge	Q _{rr}	I = 2.0 dl/dt = 100.0/up T = 25.00		22	40	nC	
Reverse Recovery Fall Time	t _a	t_{a} $t_{F} = -2 A, di/dt = 100 A/\mu s, t_{J} = 25 C$		11		ns	
Reverse Recovery Rise Time	t _b			23			

Notes:

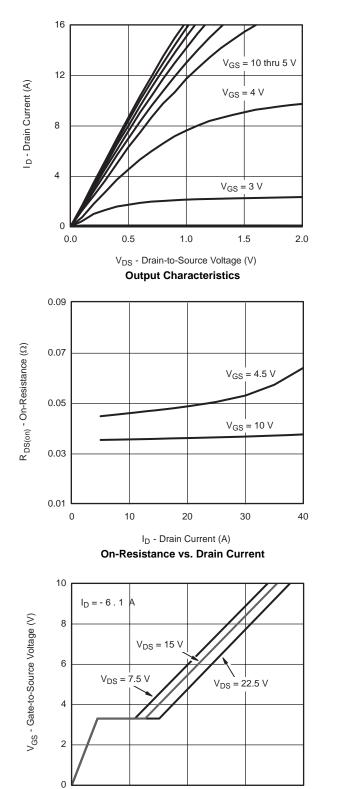
a. Pulse test; pulse width \leq 300 µs, duty cycle \leq 2 %.

b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

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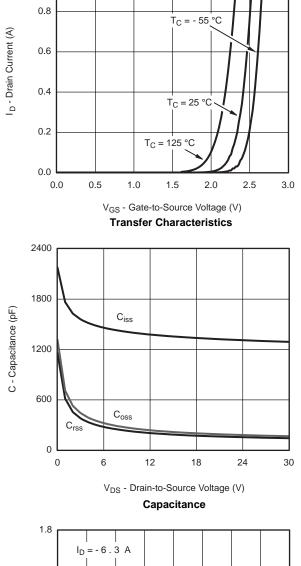
Qg - Total Gate Charge (nC)

Gate Charge

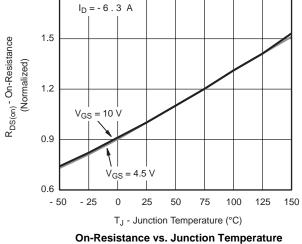
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TYPICAL CHARACTERISTICS 25 C, unless otherwise noted

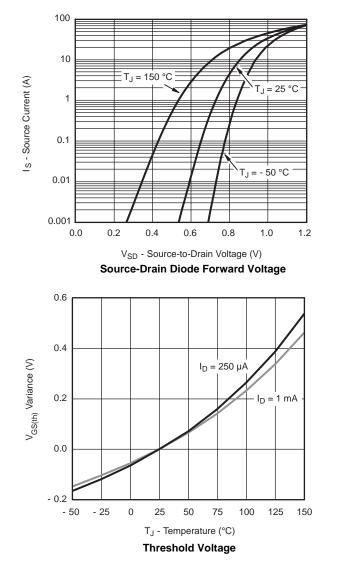


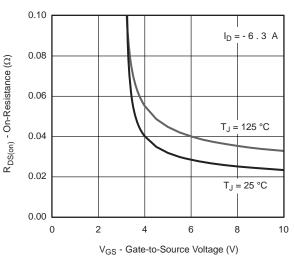
1.0



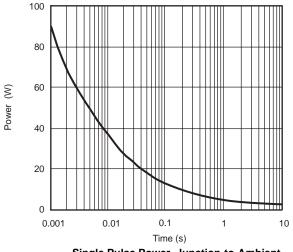


TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

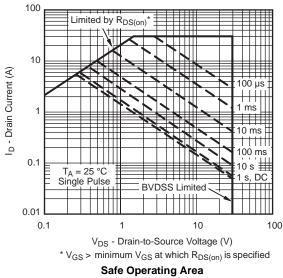




On-Resistance vs. Gate-to-Source Voltage

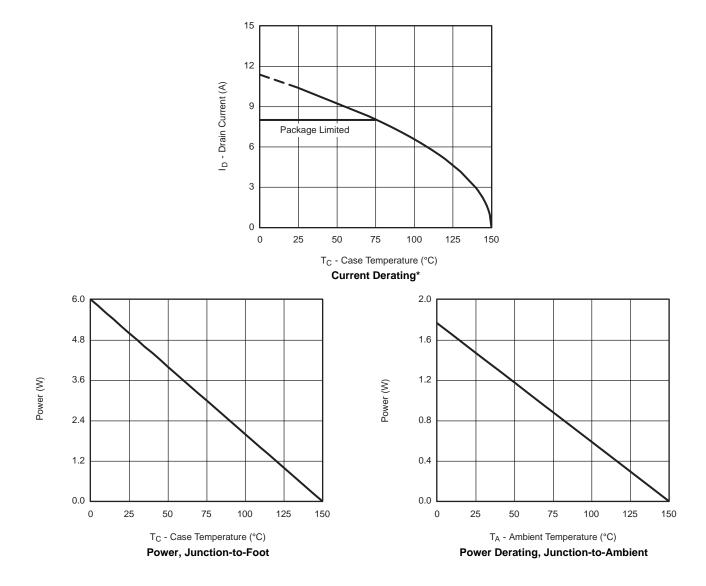


Single Pulse Power, Junction-to-Ambient





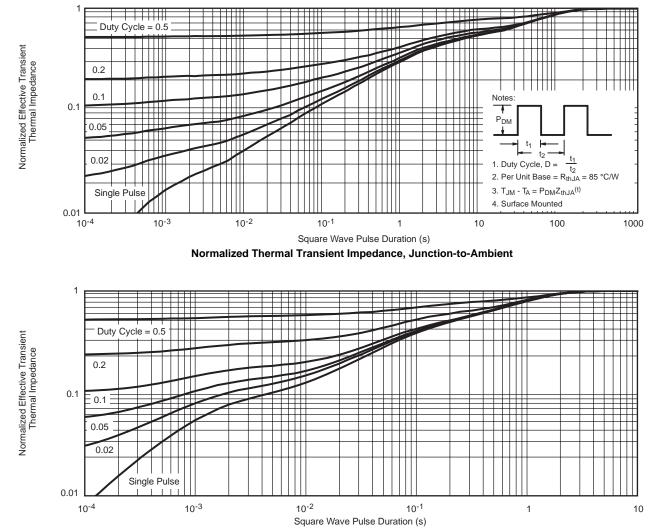
TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



* The power dissipation P_D is based on $T_{J(max)}$ = 150 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.

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TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



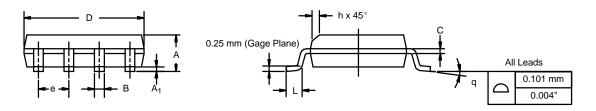
Normalized Thermal Transient Impedance, Junction-to-Foot



SOIC (NARROW): 8-LEAD

JEDEC Part Number: MS-012

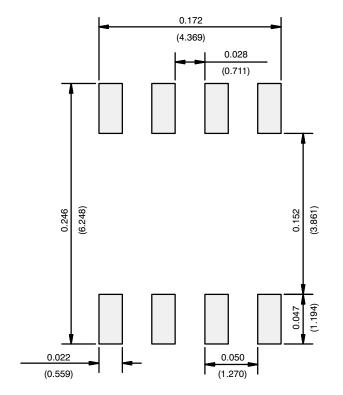




	MILLIMETERS		INC	HES		
DIM	Min	Мах	Min	Max		
A	1.35	1.75	0.053	0.069		
A ₁	0.10	0.20	0.004	0.008		
В	0.35	0.51	0.014	0.020		
С	0.19	0.25	0.0075	0.010		
D	4.80	5.00	0.189	0.196		
E	3.80	4.00	0.150	0.157		
е	1.27 BSC		0.050 BSC			
н	5.80	6.20	0.228	0.244		
h	0.25	0.50	0.010	0.020		
L	0.50	0.93	0.020	0.037		
q	0°	8°	0°	8°		
S	0.44	0.64	0.018	0.026		
ECN: C-06527-Rev. I, 11-Sep-06 DWG: 5498						



RECOMMENDED MINIMUM PADS FOR SO-8



Recommended Minimum Pads Dimensions in Inches/(mm)



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